The Yamaichi Electronics YED254 Series include sockets for manual usage only. The Test Contactors are limited up to 50,000 insertions and approx. 200 probe pins. The Test Contactors can be equipped with standard, low inductance, crown and conical style probe pins. Plating options like Palladium and CSH are available on request.

CUSTOMISED ≥0.30MM PITCH AND HINGED TYPE

SPECIFICATIONS

Contact Resistance:	≤75mΩ
Contact Force (typical):	9 to 25gf
Operating Temp. Range:	–40°C to +125°C
High Temperature Range:	–55°C to +150°C
Electrical performance:	on request
Mating Cycles:	50,000 insertions min.

MATERIALS AND FINISH

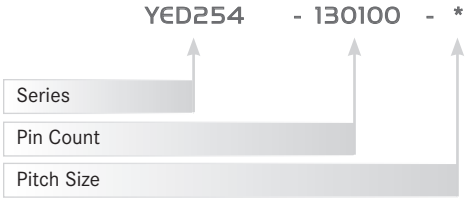
Housing:	PEEK / Anodized Aluminum
Contacts:	Beryllium Copper (BeCu) (Typical)
Plating:	Gold over Nickel (Typical)

Other materials are available on request

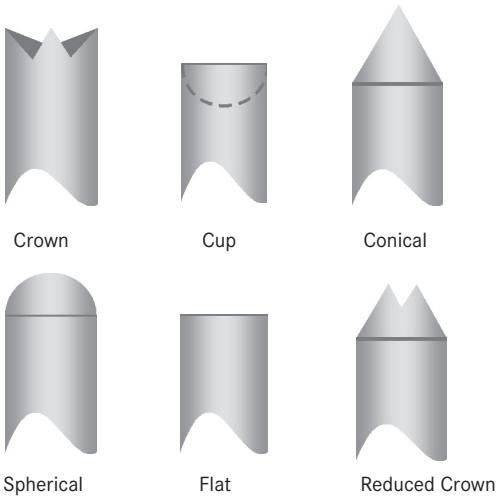
FEATURES

- Customised Test Contactor
- Easy-close cover
- Outstanding performance
- Lab applications
- Higher temperature range available
- Optional: Serial number and data matrix code

PART NUMBER

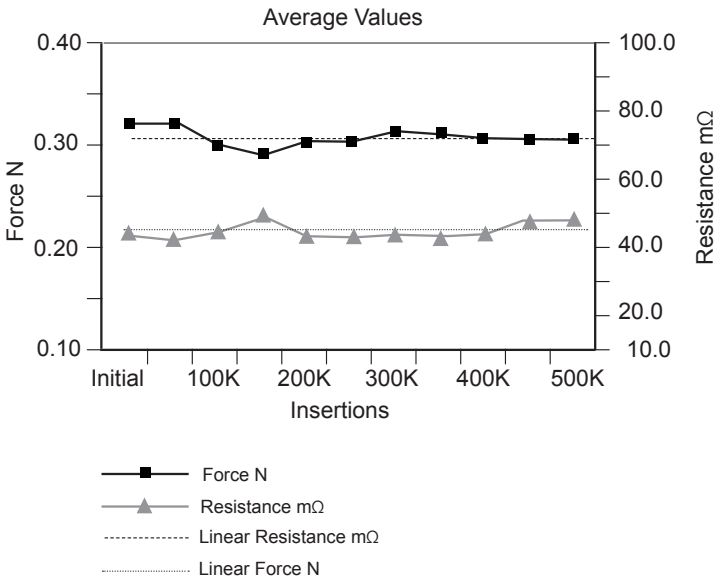


TYPICAL PIN TIP STYLES

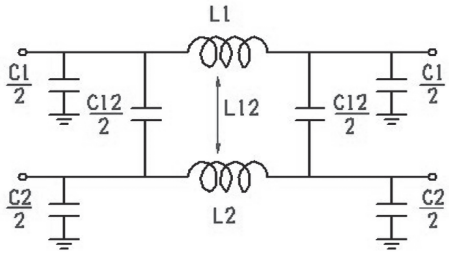


TYPICAL EXAMPLE PIN CHARACTERISTICS*

* 0.40mm pitch configuration, values based on internal Yamaichi testing



Lumped Coupled Model

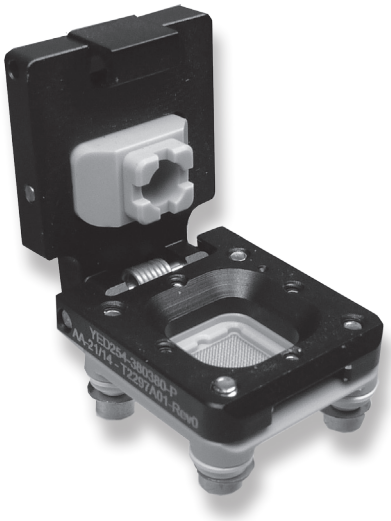


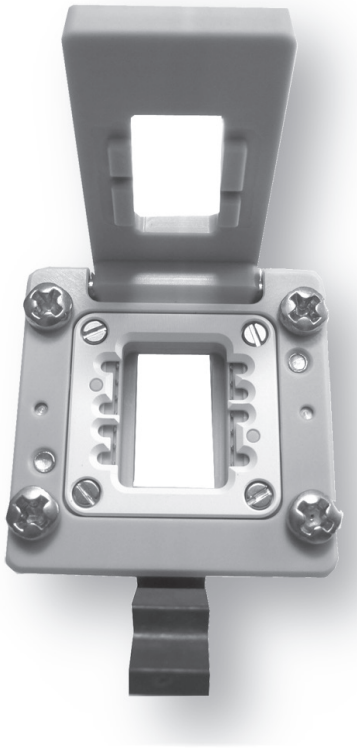
Self Inductance	L1 - L2	0.933 nH
Mutual Inductance	L12	0.149 nH
Self Capacitance	L1 - L2	0.629 pF
Mutual Capacitance	C12	0.129 pF

The Test Contactors are design for initial lab testing, HTOL, HAST, ELFR, failure analysis and many other applications:

EXAMPLES

FEATURES
- Small outline
- Low pin count
- ePad contact for QFN/SO/QFP
- Spring loaded lid





FEATURES
- Customized footprint
- Lead spacer for optimized device guiding for QFP / SO devices
- High performance materials

FEATURES
- Suitable for microscopes
- Optional optical glass / plastics
- Customized socket footprint
- Outer dimensions according to customer requirements